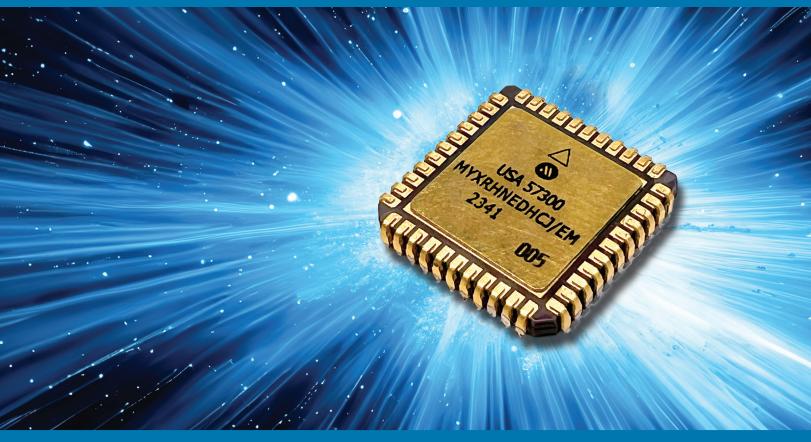


Nuclear Event Detector

Product Brief



The Micross MYXRHNEDHCJ series Nuclear Event Detectors (NED) are screened to class H & K, and feature integrated differential drivers – providing SWaP savings, improved overall noise immunity, 300% greater radiation dose sensitivity, and 25% faster response times compared with legacy devices.



KEY FEATURES

- · Gamma Dose Rate Sensitivity Threshold Range Adjustable from 5×10^4 to 2×10^7 rads (Si) / sec.
- · 44 Pin J-Lead SMT Package (.650in x .650in x .113in)
- · Integrated Differential Line Drivers and Receivers
 - · Eliminates the Need for Sheilding External Drivers and Recievers
- · Radiation Specifications
 - Total Dose (Device Survivability): 1 x 10⁶ rads (Si)
 - Dose Rate (Operate Through): 1 x 1012 rads (Si) / sec.
 - Neutron Fluence (Operate Through): 5 x 10¹³ neutrons / cm²
- · Delay from Radiation Detected to Output Signal Asserted: 15ns
- · 3.3V Power Requirement
- · -55 to +125°C Temperature Range
- Differential Line Drivers and Receivers All Operate Through Prompt Dose Without Extra Shielding

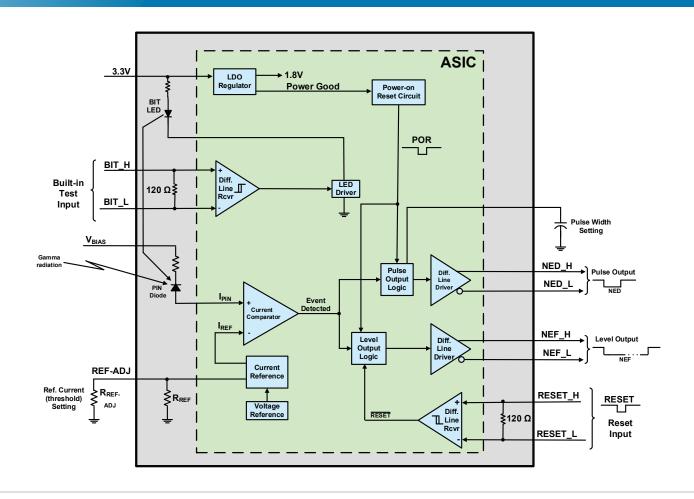
BENEFITS

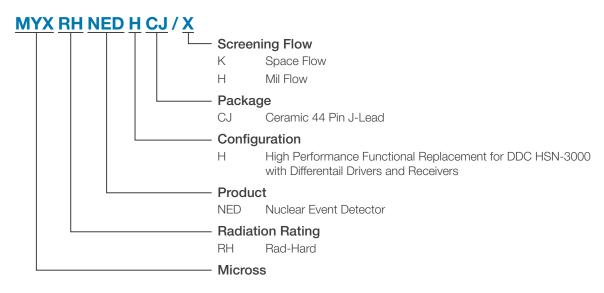
- · 4X Lower Minimum Dose Rate Sensitivity
- 25% Faster Response Time Enabling a More Rapid Shutdown of Critical Electronics
- · Improved Noise Immunity
- Use Output Signal to Shut Down Power Supplies, Take Processors Offline and Block Memory Write Operations
- · Manufactured on US soil in the Jazz Semiconductor Trusted Foundry
- Improvements in Obsolescence Mitigation with In-House Sourced PIN Diode and ASIC

APPLICATIONS

- · Aircrafts and Drones
- · Missiles and Bombs
- · Satellites
- · Military Ground Vehicles
- · Nuclear Material Storage

NED with Integrated Line Drivers & Recievers







Need Information?

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